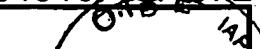
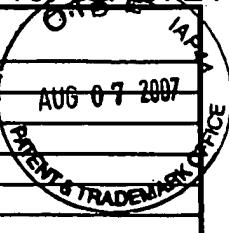


IDS Form PTO/SB/08: Substitute for form 1449A/PTO				Complete if Known	
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b> <i>(Use as many sheets as necessary)</i>				<b>Application Number</b> 10/534,510 <b>Filing Date</b> October 31, 2005 <b>First Named Inventor</b> Michael Haft <b>Art Unit</b> 2169 <b>Examiner Name</b> Chin Ju Yang	 U.S. PATENT & TRADEMARK OFFICE
Sheet	1	of	1	<b>Attorney Docket Number</b> 05281.0015	



## U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS

## FOREIGN PATENT DOCUMENTS

Examiner Initials <sup>1</sup>	Cite No. <sup>1</sup>	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation <sup>8</sup>
		Country Code <sup>3</sup> Number <sup>4</sup> Kind Code <sup>5</sup> (if known)				
/SFL/	3	WO 02/10954 A2	02-07-2002			
/SFL/	4	WO 99/28832 A2	06-10-1999			

## NONPATENT LITERATURE DOCUMENTS

Examiner Initials	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation <sup>6</sup>
/SFL/	5	Bishop, Christopher M., "Latent Variable Models," M. I. Jordan (ed.), Learning in Graphical Models, 371-403 (1998).	
/SFL/	6	Tanner, Martin A., "Tools for Statistical Inference," Springer, New York, 3:64-135 (1996).	
/SFL/	7	Neal, Radford M., "A View of the EM Algorithm that Justifies Incremental, Sparse, and Other Variants," M. I. Jordan (ed.), Learning in Graphical Models, 355-368 (1998).	
/SFL/	8	Heckerman, David, "Bayesian Networks for Data Mining," Data Mining and Knowledge Discovery, 1:79-119 (1997).	
/SFL/	9	Abstract of Hofmann, R. , "Lernen der Struktur nichtlinearer Abhangigkeiten mit graphischen Modellen," ISBN:3-89825-131-4.	
/SFL/	10	International Search Report for PCT/EP 03/11655 dated 19 October 2004.	
Examiner Signature	/Shew Fen Lin/		Date Considered
			02/11/2008

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /SFL/